

Application/Control No.	Applicant(s)/Patent under Reexamination
10/734,297	OHGANE ET AL.
Examiner	Art Unit
Tae H. Yoon	1714

	SEARCHED						
Class	Subclass	Date	Examiner				
524	494	8-18-06	4				
	430						

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
EAST Inventor Search	f-27-06	2		
Inventor Search				